

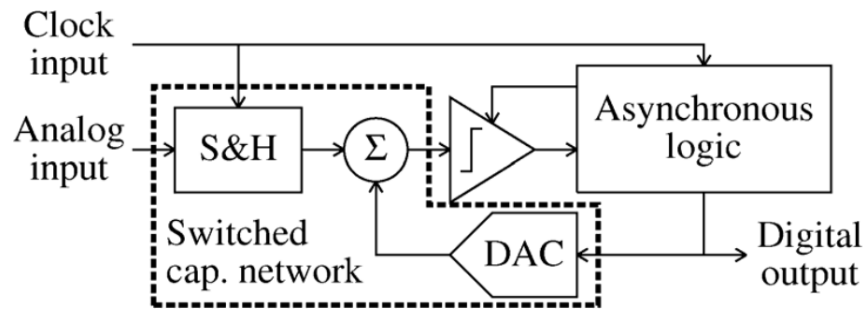
KGD: 4-way Time-Interleaved Asynchronous SAR ADC in PTM 45nm CMOS

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I. Introduction

In this design an 8-bit 1GS/s SAR ADC has been implemented.

SAR Architecture:



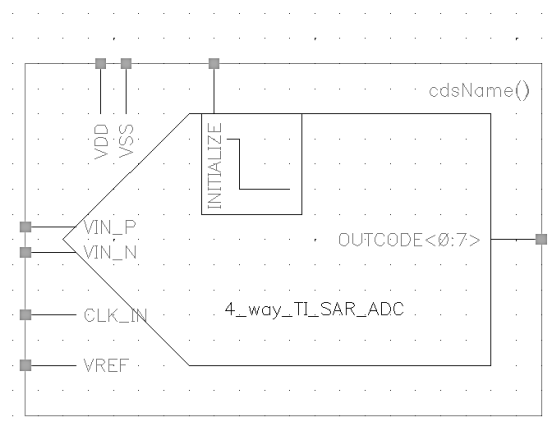
Architecture of Single SAR ADC

The major blocks in the design are:

- Clock generation
- Bootstrap sampler and Capacitive DAC
- Comparator
- SAR logic

Description:

The Top-level cell: chip_core_TI – An 8-bit 1GS/s 4-way Time-interleaved SAR ADC

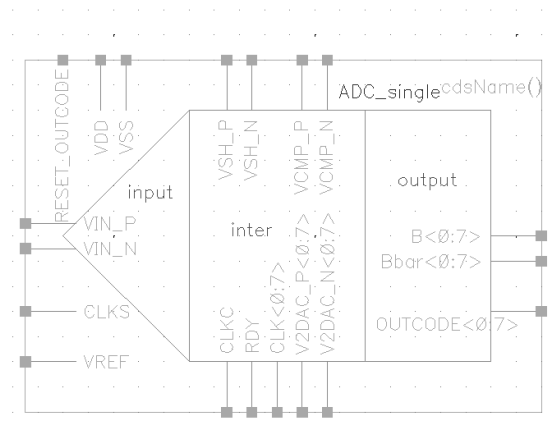


Pin Configuration:

Pin Name	Input or output	Specification
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VDD	Input	Power Supply, 1.1V
VSS	Input	Ground
CLK_IN	Input	Input Clock 1GHz
VREF	Input	Reference voltage, 1V
INITIALIZE	Input	Initialize clock generation
VIN_P, VIN_N	Input	Differential input signal, common mode voltage 0.55V
OUTCODE<0:7>	output	8-bit output code

The Top-level cell: chip_core – An 8-bit 250MS/s SAR ADC

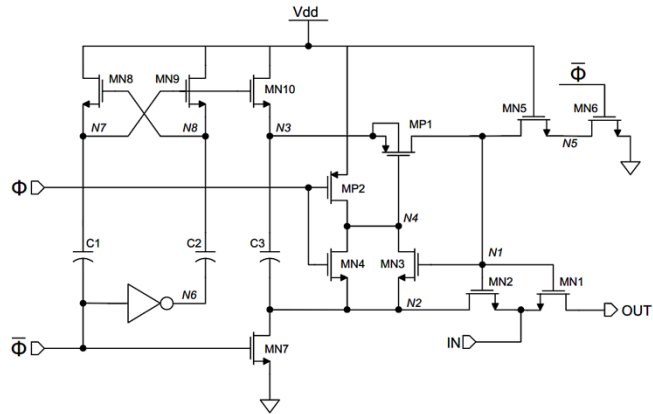


Pin Configuration:

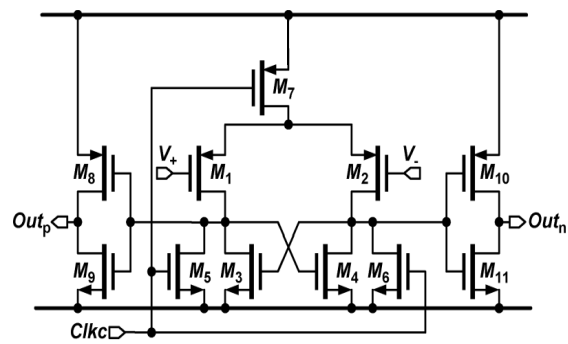
Pin Name	Input or output	Specification
VDD	Input	Power Supply, 1.1V
VSS	Input	Ground
CLK_S	Input	Input Clock 250MHz, 20% duty cycle
VREF	Input	Reference voltage, 1V
VIN_P, VIN_N	Input	Differential input signal, common mode voltage 0.55V
RESET_OUTCODE	Input	Reset output latch
OUTCODE<0:7>	output	8-bit output code

Schematic of cells

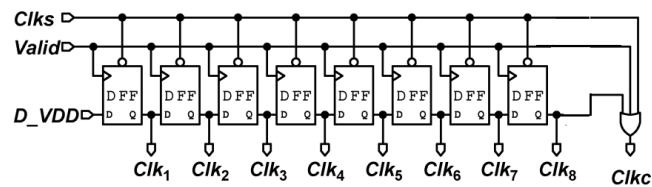
Schematic of bootstrap sampler



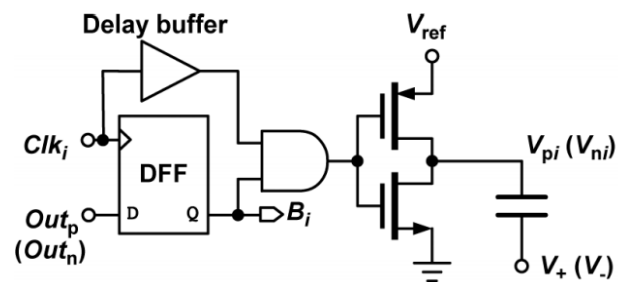
Schematic of comparator



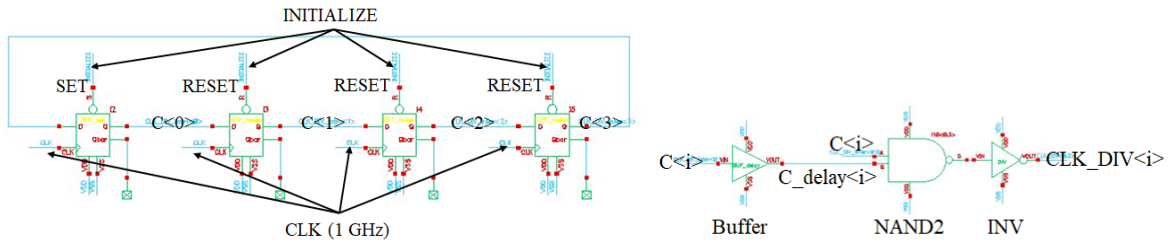
Schematic of SAR control logic



Schematic of DAC control logic



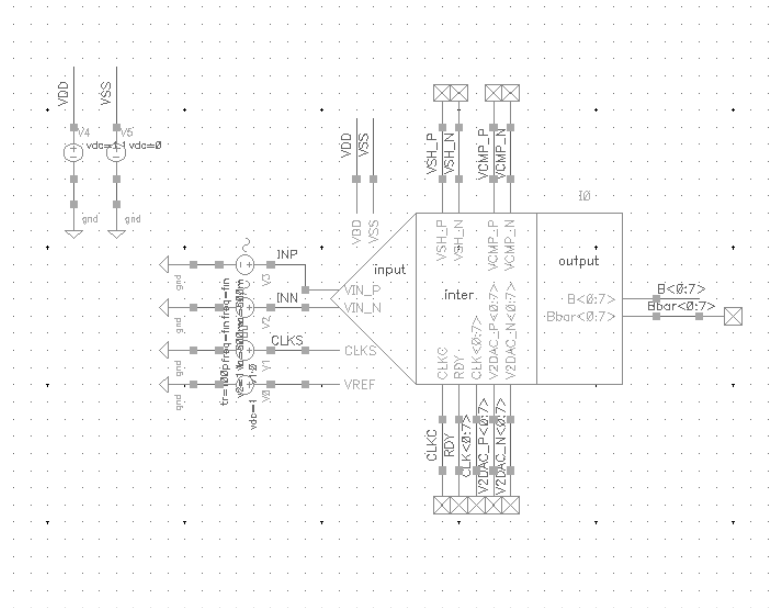
Schematic of Clock generation

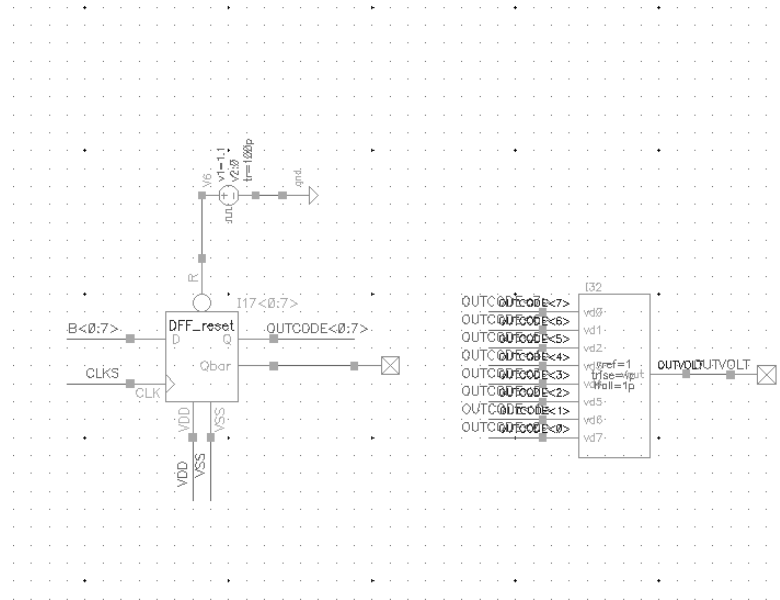


Test Bench:

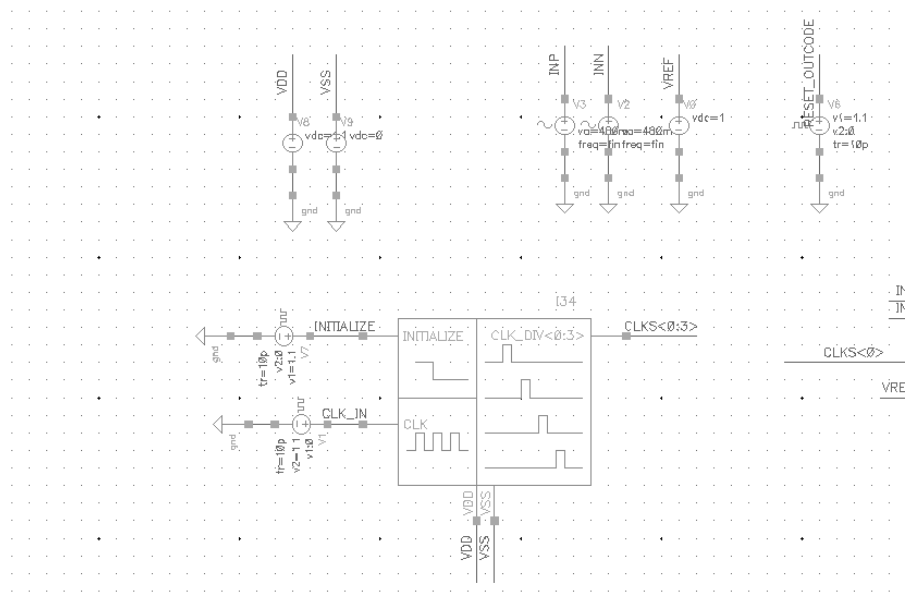
Locking time evaluation:

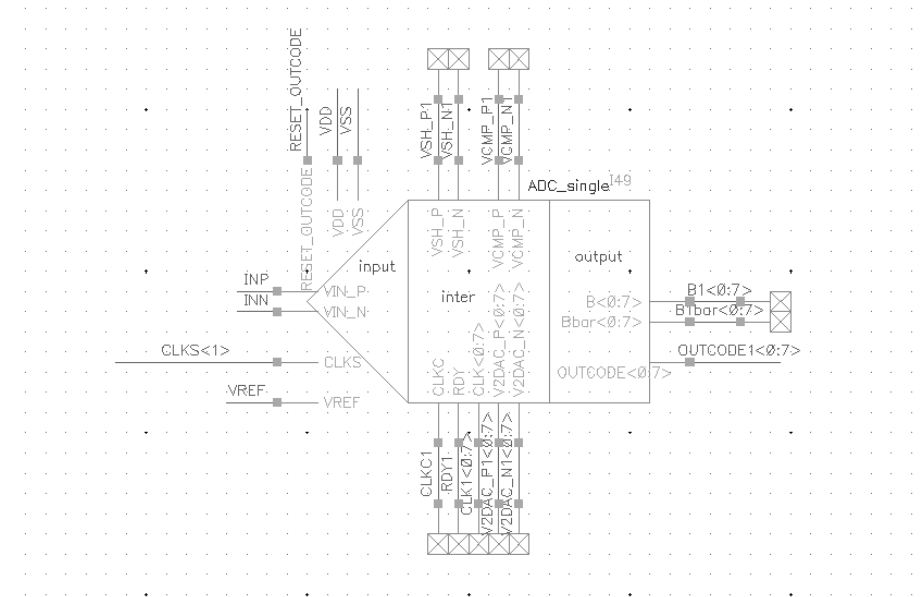
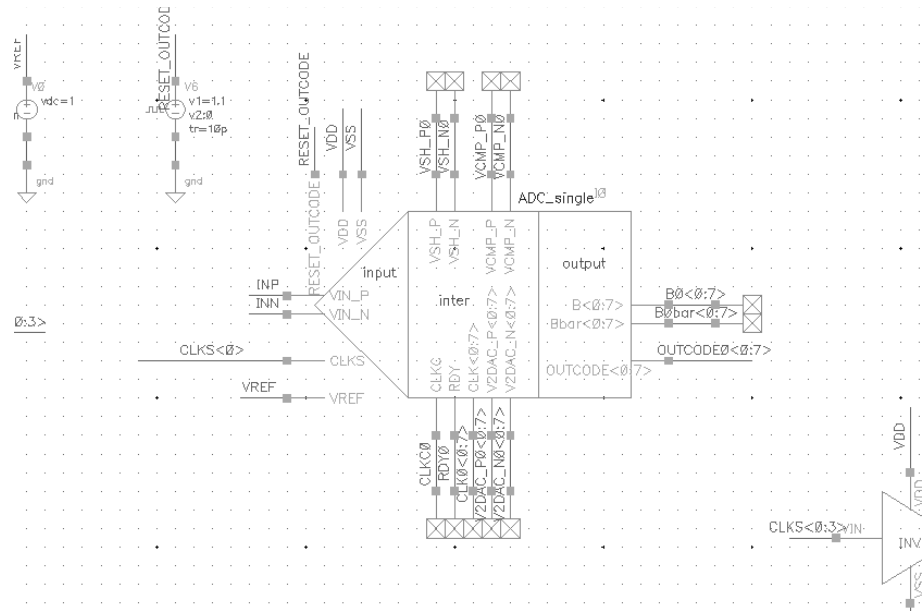
1. `tb_chip_core`: Testbench for single channel SAR ADC

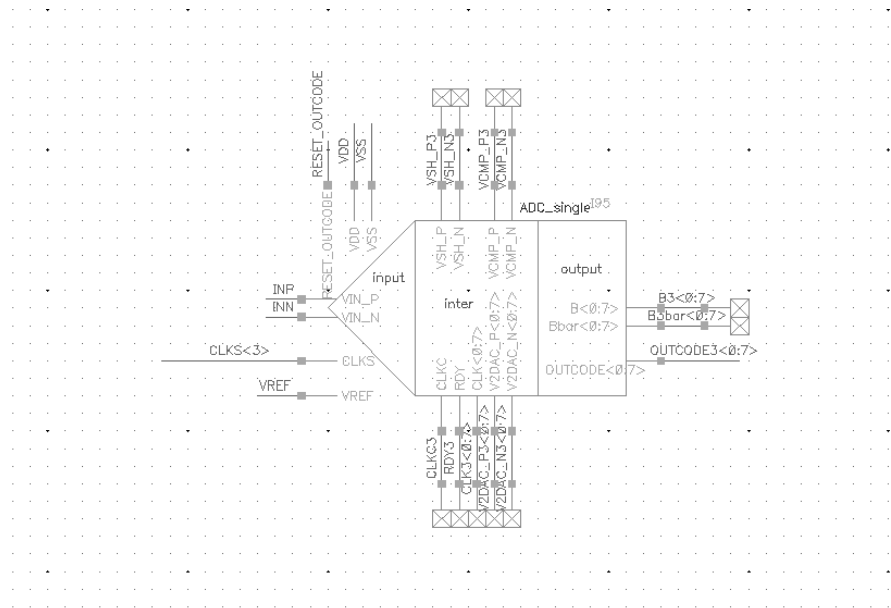
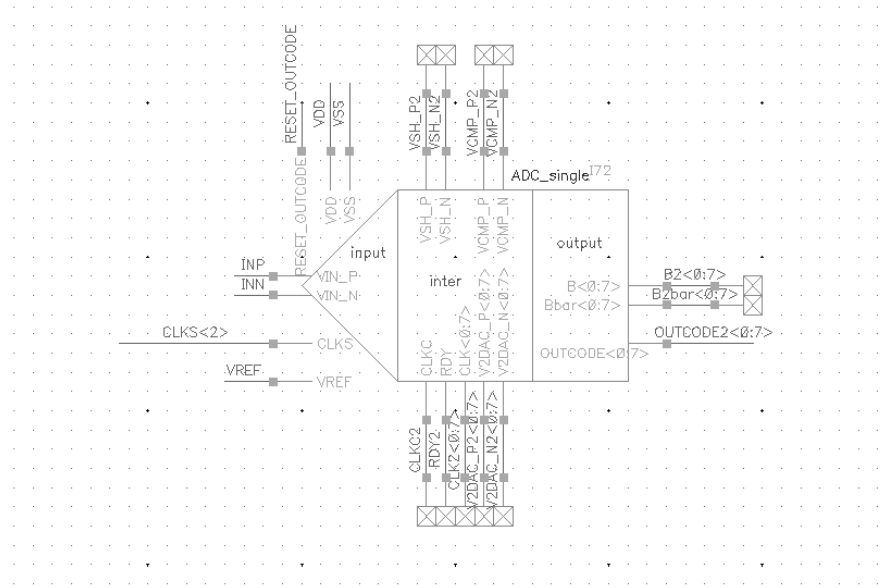


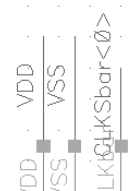
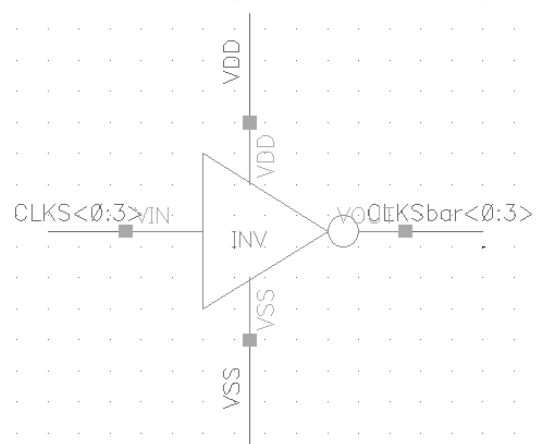


2. tb_chip_core_TI: Testbench for time-interleaved SAR ADC

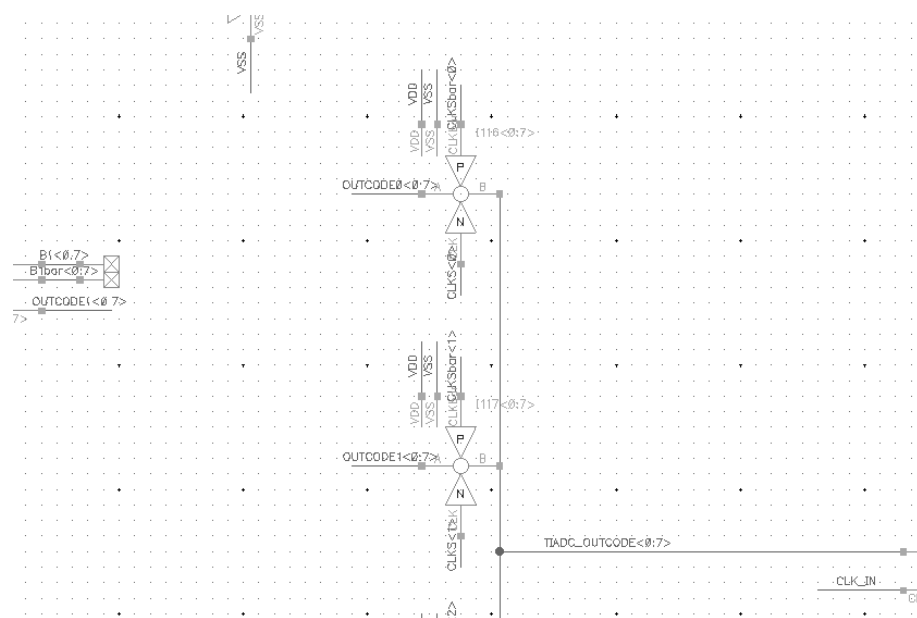


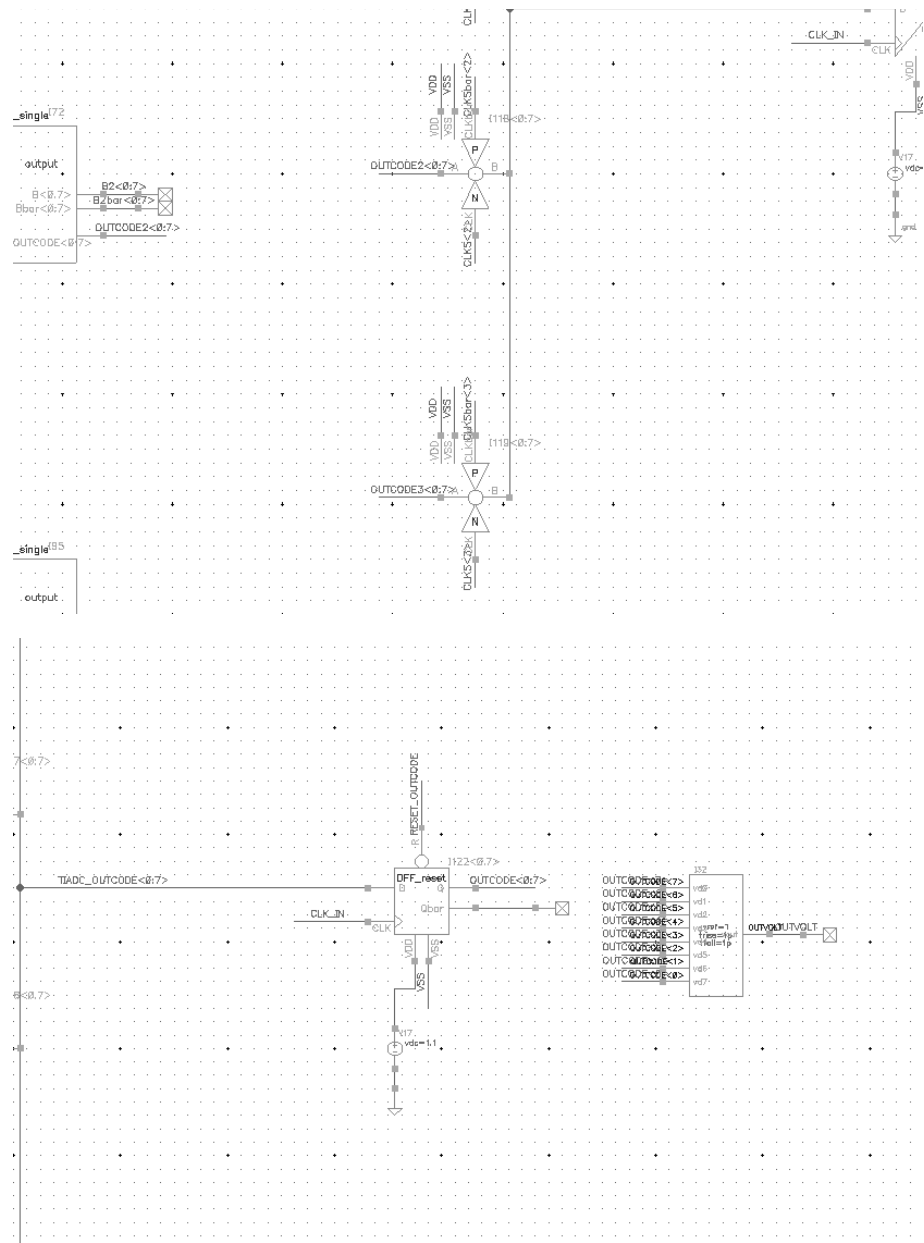






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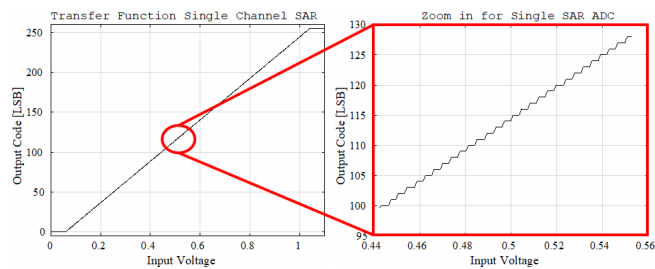




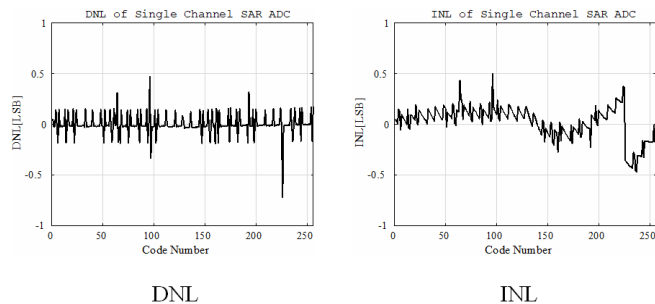
Simulation Results:

Single ADC

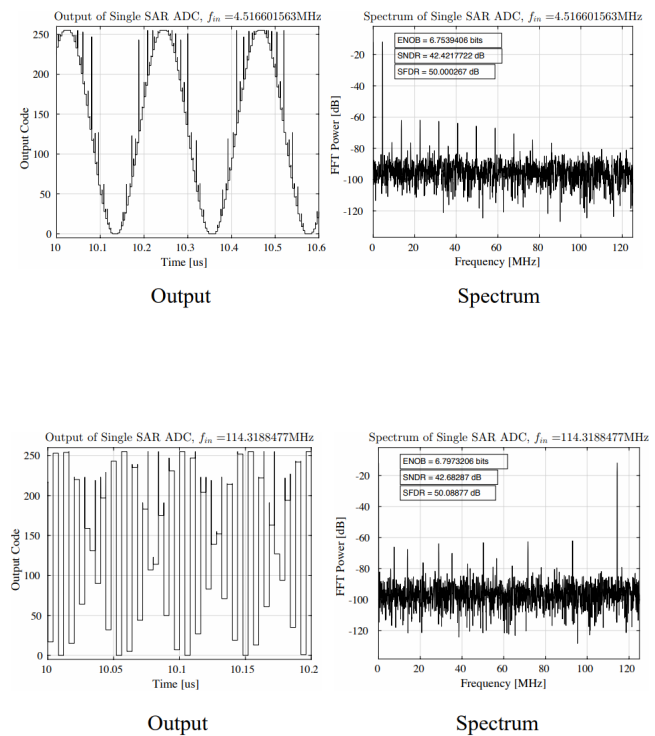
Single ADC Static Test:

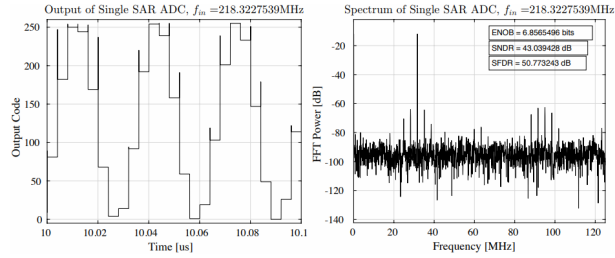


Ramp signal test



Single ADC Dynamic Tests:

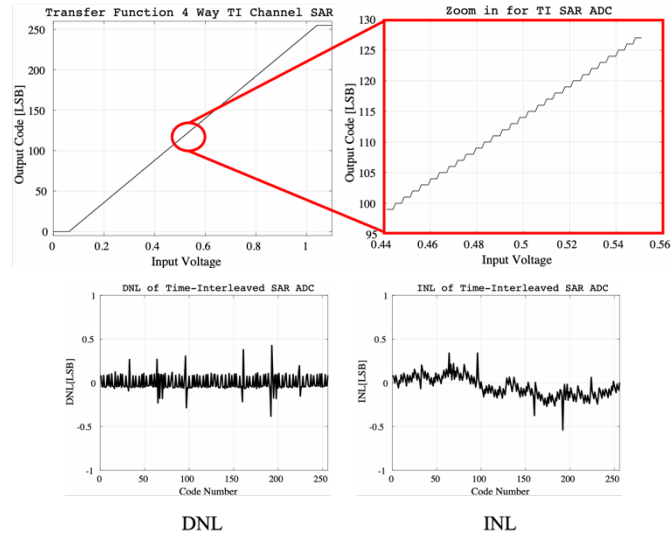




Output

Spectrum

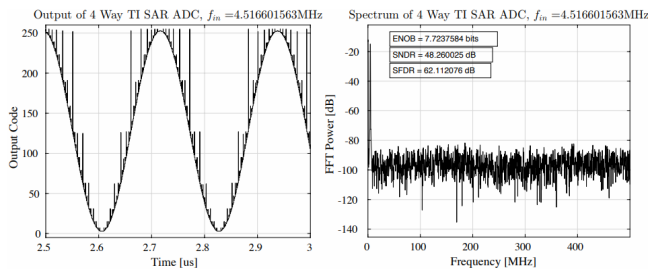
Time Interleaved ADC static test



DNL

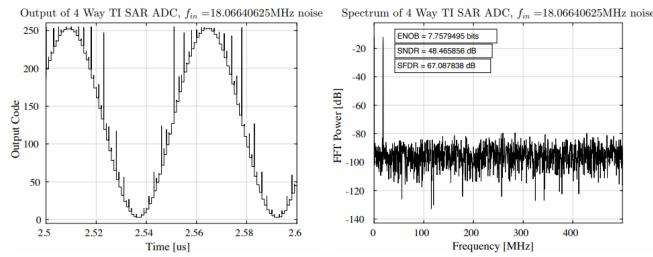
INL

Time Interleaved ADC Dynamic Tests:



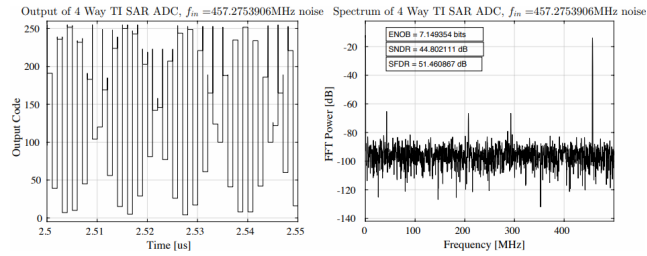
Output

Spectrum



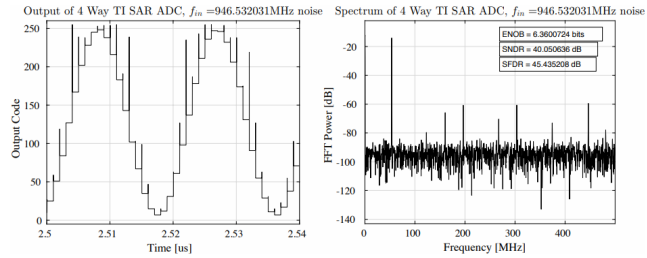
Output

Spectrum



Output

Spectrum



Output

Spectrum

Performance summary

Single ADC

Specifications	$f_n = 4.52 \text{ MHz}$	$f_n = 114.32 \text{ MHz}$
Resolution [bit]	8	8
Sampling Rate [MS/s]	250	250
Input Swing [mV]	1000	1000
ENOB [bit]	6.75	6.80
SNDR [dB]	42.42	42.68
SFDR [dB]	50.00	50.09
Power [mW]	50.6	50.8
FoM [pJ/conv-step]	1.88	1.82

Time interleaved ADC

Specifications	$f_n = 4.52 \text{ MHz}$	$f_n = 18.07 \text{ MHz}$	$f_n = 457.28 \text{ MHz}$
Resolution [bit]	8	8	8
Sampling Rate [GS/s]	1	1	1
Input Swing [mV]	1000	1000	1000
ENOB [bit]	7.72	7.75	7.15
SNDR [dB]	48.26	48.47	44.80
SFDR [dB]	62.11	67.09	51.46
Power [mW]	254.6	255.0	254.8
FoM [pJ/conv-step]	1.21	1.18	1.79

Power breakdown

